## **STL12N65M2**



# N-channel 650 V, 0.62 Ω typ., 5 A MDmesh™ M2 Power MOSFET in a PowerFLAT™ 5x6 HV package

Datasheet - production data

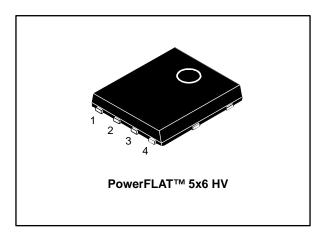
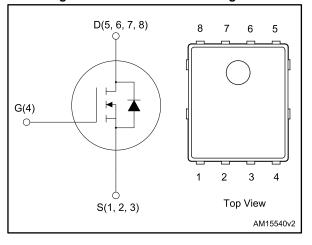


Figure 1: Internal schematic diagram



## **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>	Ртот
STL12N65M2	650 V	0.75 Ω	5 A	48 W

- Extremely low gate charge
- Excellent output capacitance (C<sub>OSS</sub>) profile
- 100% avalanche tested
- Zener-protected

## **Applications**

Switching applications

## **Description**

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

**Table 1: Device summary** 

Order code	Marking	Package	Packing
STL12N65M2	12N65M2	PowerFLAT™ 5x6 HV	Tape and reel

Contents STL12N65M2

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STL12N65M2 Electrical ratings

# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>GS</sub>	Gate-source voltage	±25	V
1	Drain current (continuous) at T <sub>case</sub> = 25 °C	5	Α
I <sub>D</sub>	Drain current (continuous) at T <sub>case</sub> = 100 °C	3.15	A
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	20	Α
P <sub>TOT</sub>	Total dissipation at T <sub>case</sub> = 25 °C	48	W
dv/dt <sup>(2)</sup>	Peak diode recovery voltage slope	15	V/ns
dv/dt <sup>(3)</sup>	v/dt <sup>(3)</sup> MOSFET dv/dt ruggedness		V/IIS
T <sub>stg</sub>	Storage temperature	-55 to 150	°C
T <sub>j</sub>	T <sub>j</sub> Operating junction temperature		

#### Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case	2.6	0CAN
R <sub>thj-pcb</sub> <sup>(1)</sup>	ermal resistance junction-pcb 50		°C/W

## Notes:

**Table 4: Avalanche characteristics** 

Symbol	Parameter	Value	Unit
I <sub>AR</sub> <sup>(1)</sup>	Avalanche current, repetitive or not repetitive	0.5	Α
E <sub>AS</sub> <sup>(2)</sup>	Single pulse avalanche energy		mJ

### Notes:

 $<sup>^{\</sup>left(1\right)}$  Pulse width is limited by safe operating area.

 $<sup>^{(2)}</sup>$   $I_{SD} \le 5$  A, di/dt=400 A/µs;  $V_{DS}$  peak <  $V_{(BR)DSS}.$ 

 $<sup>^{(3)}</sup> V_{DS} \le 520 V.$ 

 $<sup>^{(1)}</sup>$  When mounted on a 1-inch² FR-4, 2 Oz copper board.

 $<sup>^{\</sup>left(1\right)}$  Pulse width limited by  $T_{jmax}.$ 

 $<sup>^{(2)}</sup>$  starting  $T_{j}$  = 25 °C,  $I_{D}$  =  $I_{AR},\,V_{DD}$  = 50 V.

Electrical characteristics STL12N65M2

## 2 Electrical characteristics

(T<sub>case</sub> = 25 °C unless otherwise specified)

Table 5: Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	650			V
	Zaro goto voltago drain	$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}$			1	
I <sub>DSS</sub>	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V},$ $T_{case} = 125 \text{ °C}$			100	μΑ
I <sub>GSS</sub>	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = 25 \text{ V}$			±10	μΑ
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3	4	V
R <sub>DS(on)</sub>	Static drain-source on- resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 3 A		0.62	0.75	Ω

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub>	Input capacitance		-	410	1	
Coss	Output capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz},$	-	20	-	pF
C <sub>rss</sub>	Reverse transfer capacitance	$V_{GS} = 0 V$	-	0.9	-	ρı
Coss (1) eq.	Equivalent output capacitance	$V_{DS} = 0$ to 520 V, $V_{GS} = 0$ V	-	83	-	pF
$R_{G}$	Intrinsic gate resistance	f = 1 MHz open drain	-	6.4	-	Ω
Qg	Total gate charge	$V_{DD} = 520 \text{ V}, I_D = 7 \text{ A},$	-	12.5	-	
Q <sub>gs</sub>	Gate-source charge	V <sub>GS</sub> = 10 V (see <i>Figure 15</i> :	-	3.2	-	nC
$Q_gd$	Gate-drain charge	"Gate charge test circuit")	-	5.8	-	

### Notes:

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	$V_{DD} = 325 \text{ V}, I_D = 3.5 \text{ A}$	-	9.5	-	
t <sub>r</sub>	Rise time	$R_G = 4.7 \Omega$ , $V_{GS} = 10 V$ (see Figure 14: "Switching times	-	7.5	-	
t <sub>d(off)</sub>	Turn-off delay time	test circuit for resistive load"	-	26	-	ns
t <sub>f</sub>	Fall time	and Figure 19: "Switching time waveform")	-	15	-	

 $<sup>^{(1)}</sup>$   $C_{oss\ eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

Table 8: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		-		5	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		20	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	$V_{GS} = 0 \text{ V}, I_{SD} = 5 \text{ A}$	-		1.6	V
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 7.5 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	318		ns
$Q_{rr}$	Reverse recovery charge	V <sub>DD</sub> = 60 V (see Figure 16: "Test circuit for inductive load	-	2.5		μC
I <sub>RRM</sub>	Reverse recovery current	switching and diode recovery times")	-	15.5		Α
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 7.5 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	437		ns
Q <sub>rr</sub>	Reverse recovery charge	$V_{DD}$ = 60 V, $T_j$ = 150 °C (see Figure 16: "Test circuit for	-	3.2		μC
I <sub>RRM</sub>	Reverse recovery current	inductive load switching and diode recovery times")	-	15		Α

## Notes:

 $<sup>^{\</sup>left( 1\right) }$  Pulse width is limited by safe operating area.

 $<sup>^{(2)}</sup>$  Pulse test: pulse duration = 300  $\mu s,$  duty cycle 1.5%.

# 2.1 Electrical characteristics (curves)

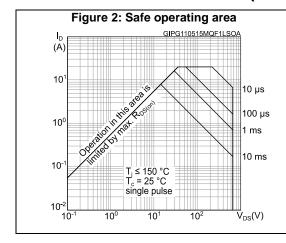
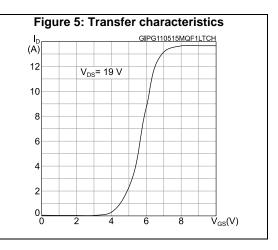
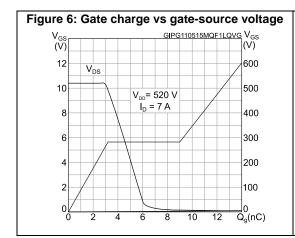
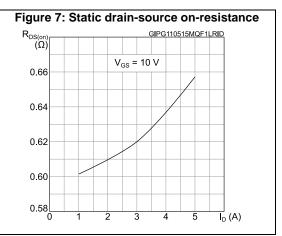


Figure 3: Thermal impedance  $\begin{array}{c} \text{K} \\ \delta = 0.5 \\ \hline 0.2 \\ \hline 10^{-1} \\ \hline \end{array}$ 







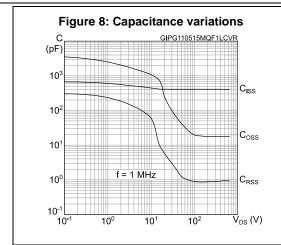


Figure 10: Normalized on-resistance vs temperature

R<sub>DS(on)</sub> GIPG110515MQF1LRON
(norm.)

2.2

1.8

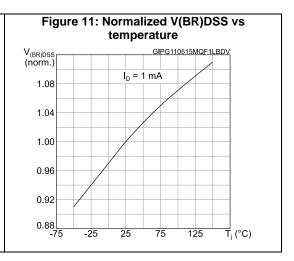
1.4

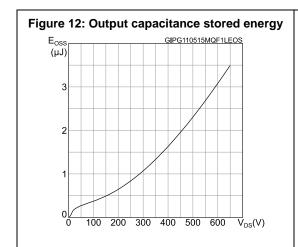
1.0

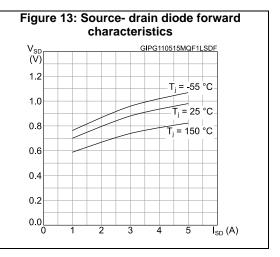
0.6

0.2

-75
-25
25
75
125
T<sub>j</sub> (°C)

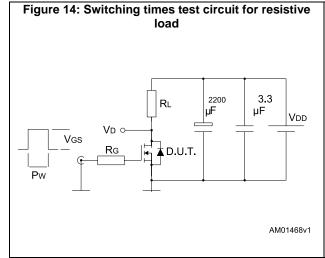






**Test circuits** STL12N65M2

#### 3 **Test circuits**



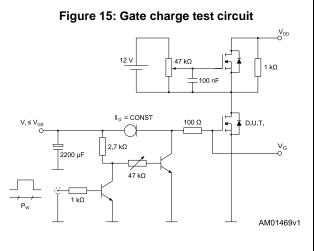


Figure 16: Test circuit for inductive load switching and diode recovery times

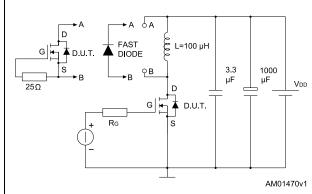
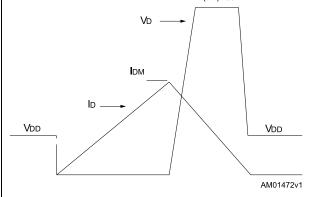
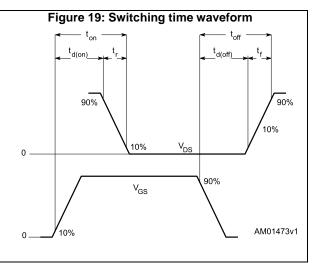


Figure 17: Unclamped inductive load test circuit 2200 Vdd AM01471v1

V(BR)DSS VD

Figure 18: Unclamped inductive waveform





# 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of  $\mathsf{ECOPACK}^{\otimes}$  packages, depending on their level of environmental compliance.  $\mathsf{ECOPACK}^{\otimes}$  specifications, grade definitions and product status are available at: www.st.com.  $\mathsf{ECOPACK}^{\otimes}$  is an ST trademark.



# 4.1 PowerFLAT 5x6 HV package information

Figure 20: PowerFLAT™ 5x6 HV package outline

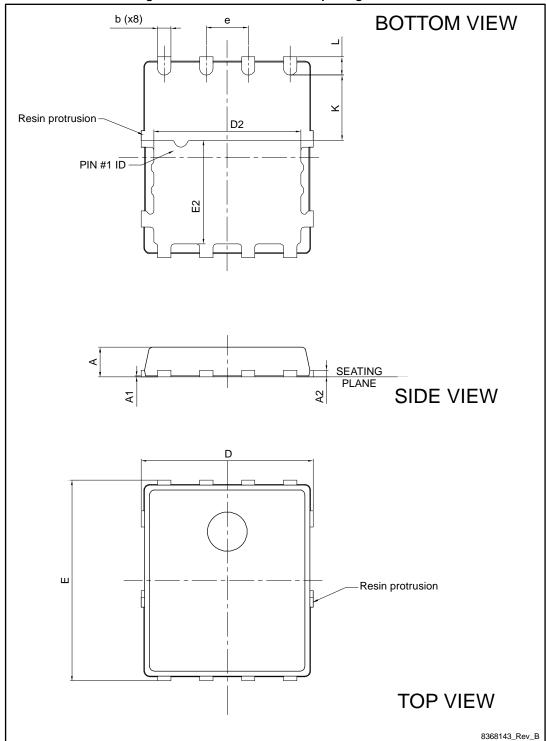
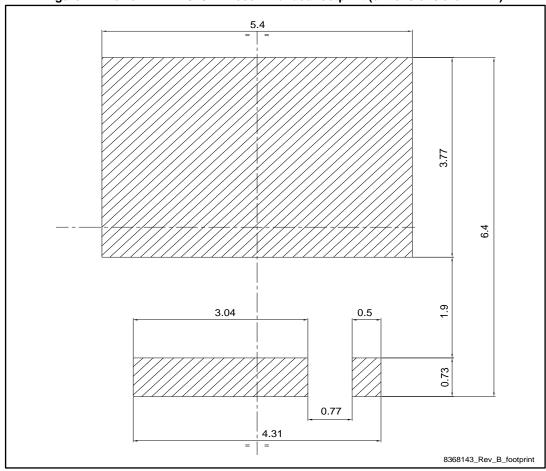


Table 9: PowerFLAT™ 5x6 HV package mechanical data

Dim.		mm	
Dim.	Min.	Тур.	Max.
Α	0.80		1.00
A1	0.02		0.05
A2		0.25	
b	0.30		0.50
D	5.00	5.20	5.40
Е	5.95	6.15	6.35
D2	4.30	4.40	4.50
E2	3.10	3.20	3.30
е		1.27	
L	0.50	0.55	0.60
K	1.90	2.00	2.10

Figure 21: PowerFLAT™ 5x6 HV recommended footprint (dimensions are in mm)



Package information STL12N65M2

# 4.2 PowerFLAT™ 5x6 packing information

Figure 22: PowerFLAT™ 5x6 tape (dimensions are in mm)

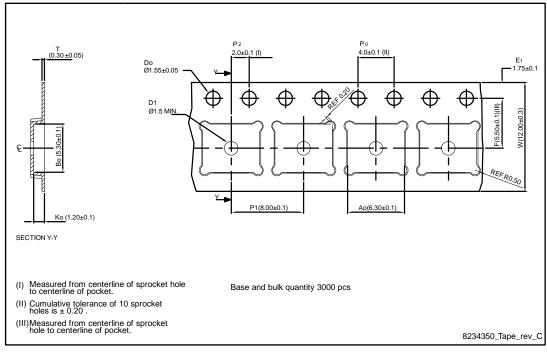
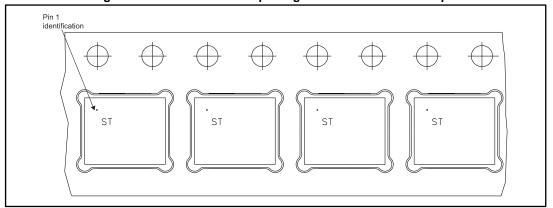


Figure 23: PowerFLAT™ 5x6 package orientation in carrier tape



R1.10

R1.10

R1.10

R1.10

R2.500

R1.10

R2.500

R1.10

Revision history STL12N65M2

# 5 Revision history

**Table 10: Document revision history** 

Date	Revision	Changes
11-May-2015	1	First release.

## **IMPORTANT NOTICE - PLEASE READ CAREFULLY**

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